

# **VALID 2017**

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## **Table of Contents**

A Method to Determine the Static NBTI Stress Time of an Embedded Component in an Integrated Circuit Puneet Ramesh Savanur and Spyros Tragoudas	1
Application of Extended Timed Automata to Automotive Integration Testing Jan Sobotka and Jiri Novak	7
Improvement of Sequential Tests in IEC-61124 Reliability Testing – Compliance Tests for Constant Failure Rate Ofer Shaham and Yefim Haim Michlin	13